

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination MA ET AL.	
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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
U	General property of gate oxide and field oxide at <a href="http://semiconductorglossary.com/">http://semiconductorglossary.com/</a> (search word field oxide & gate oxide)		
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